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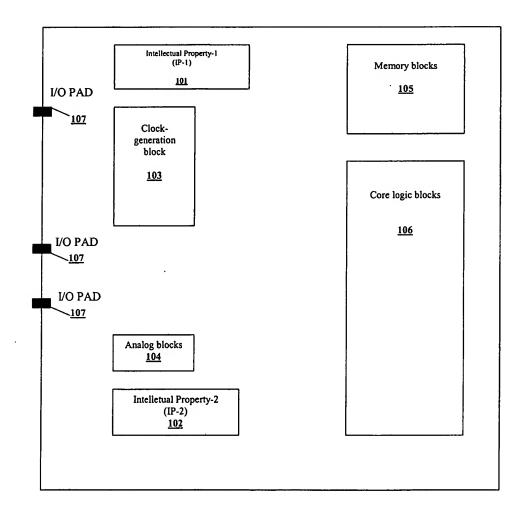


FIGURE 1

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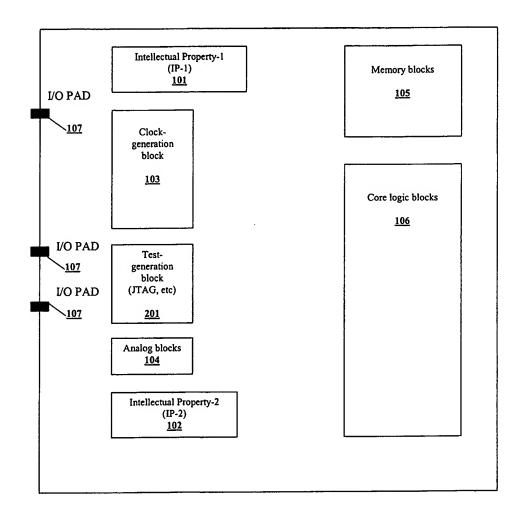


FIGURE 2

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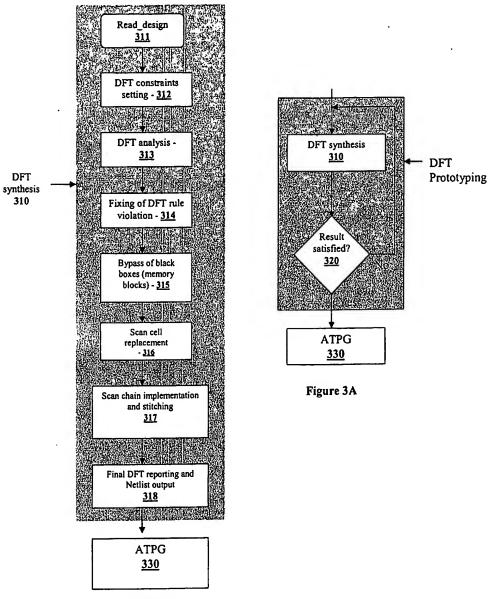
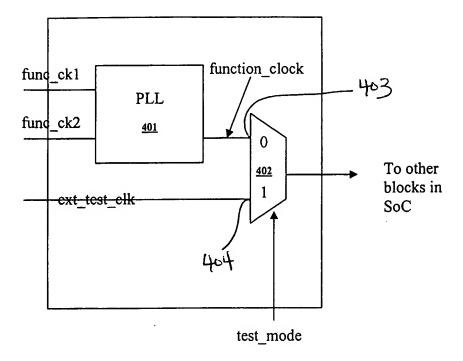


Figure 3B

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<u>400</u>

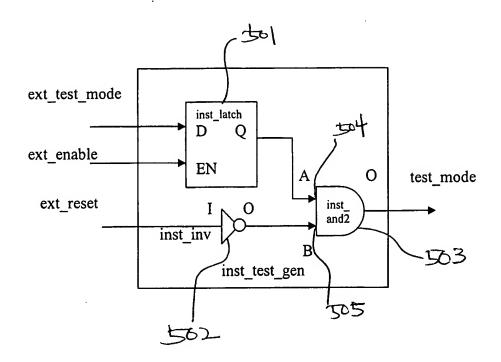
Figure 4

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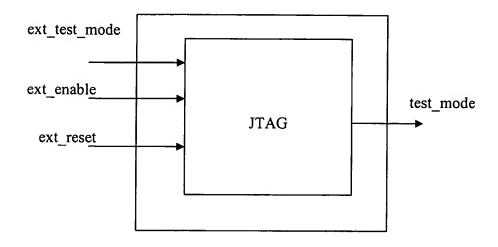
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Figure 5

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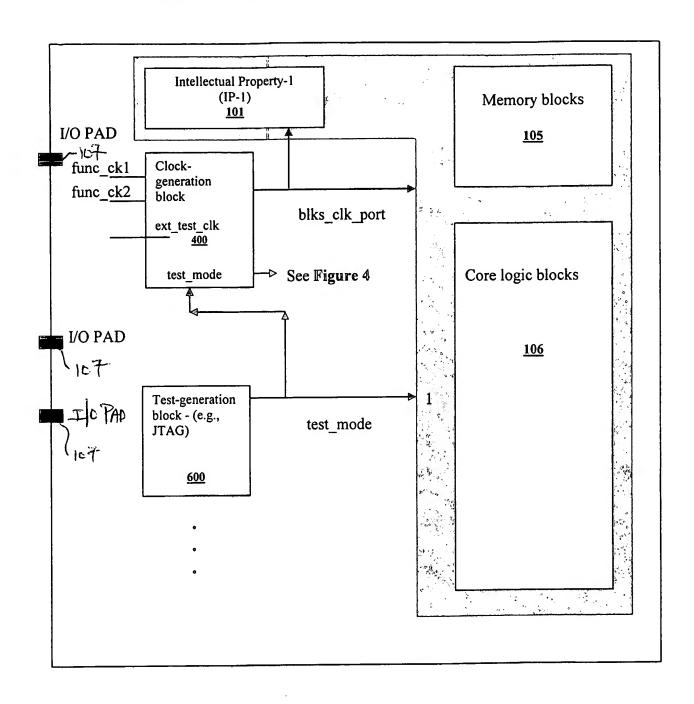


FIGURE 7

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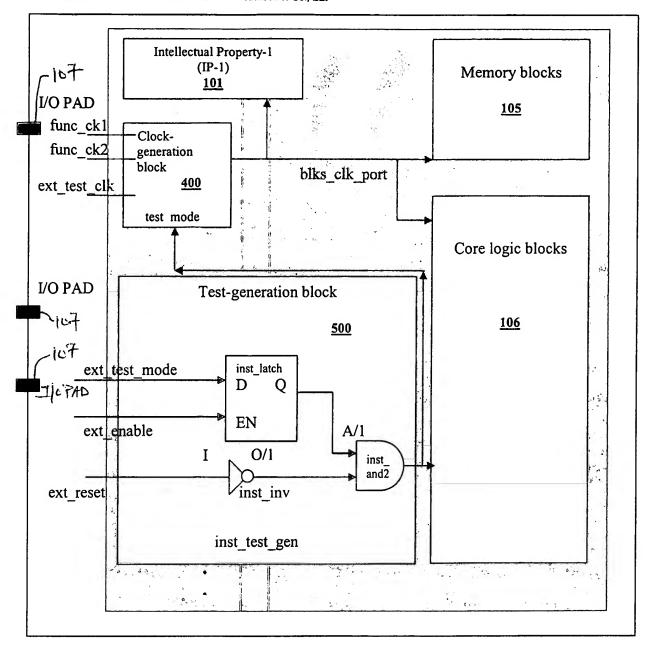


FIGURE 8

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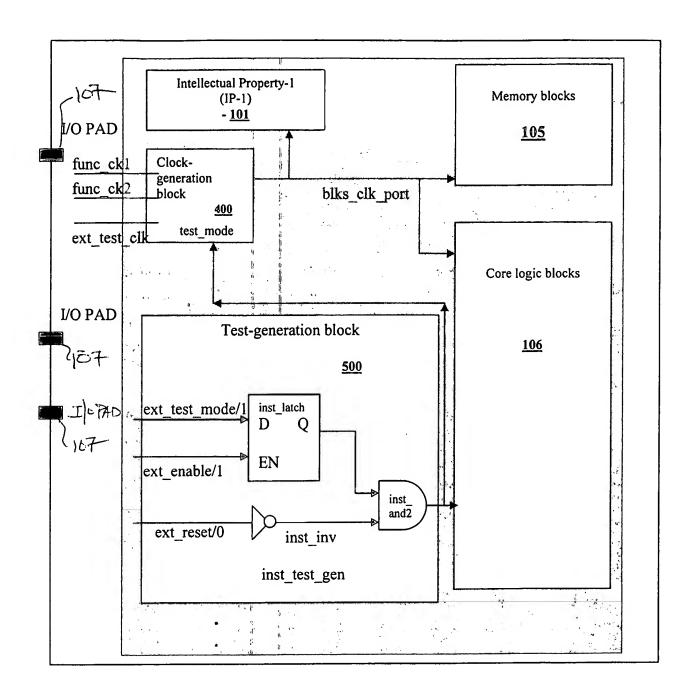


FIGURE 9

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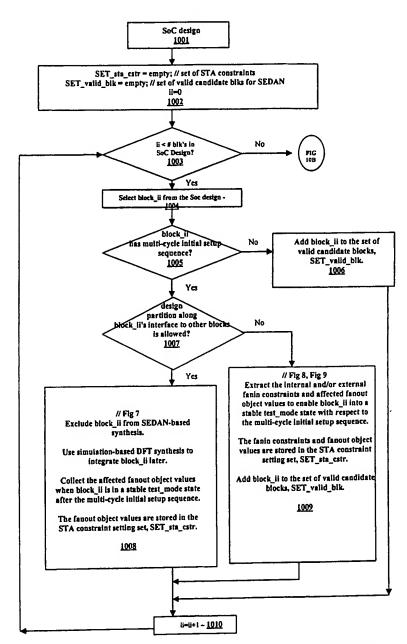


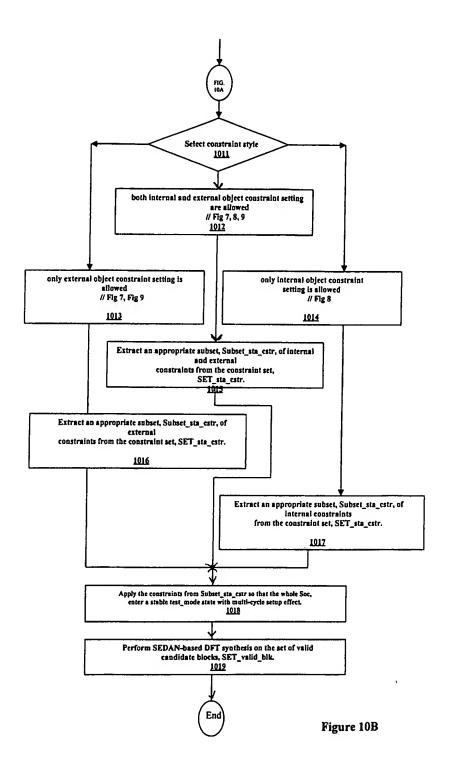
FIGURE 10A

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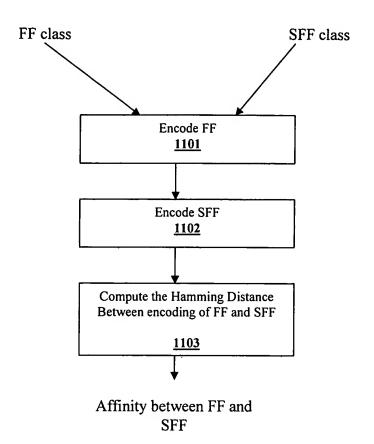


Figure 11

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